

**Notice of References Cited**

Application/Control No.

10/532,082

Applicant(s)/Patent Under  
Reexamination  
OCHI ET AL.

Examiner

ALTREV C. SYKES

Art Unit

1794

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0053646	12-2001	Tanaka et al.	442/181
	B	US-			
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	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2004256983 A	09-2004	Japan	SHIMOYAMA et al.	
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	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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